Search Notes



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Applicant(s)/Patent Under

Dinh Q Nguyen

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Class	Subclass	Date	Examiner
239	290,292,295,77,296	3/31/08	DN
101	147,148,424.1	3/31/08	DN

SEARCH NOTES

Search Notes	Date	Examiner
East search attached	3/31/08	DN

INTERFERENCE SEARCH

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	Class	Subclass	Date	Examiner	ì

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